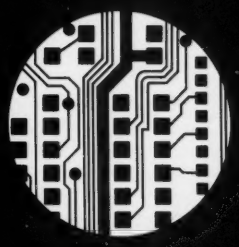

INTERNATIONAL JOURNAL OF

Microwave and Millimeter-Wave Computer-Aided Engineering

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ISSUES 1–4

Jan 1991–Oct 1991

A WILEY-INTERSCIENCE PUBLICATION
John Wiley & Sons, Inc.
NEW YORK / CHICHESTER / BRISBANE / TORONTO / SINGAPORE

ISSN 1050-1827

INTERNATIONAL JOURNAL OF

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International Journal of Microwave and Millimeter-Wave Computer-Aided Engineering (ISSN: 1050-1827) is published quarterly by John Wiley & Sons, Inc., 605 Third Avenue, New York, NY 10158.

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INTERNATIONAL JOURNAL OF MICROWAVE AND MILLIMETER-WAVE COMPUTER-AIDED ENGINEERING provides a common forum for the dissemination of research and development results in the areas of computer-aided design and engineering of microwave and millimeter-wave components, circuits, subsystems and antennas. The journal is intended to be a single source of valuable information for all engineers and technicians, microwave/mm-wave CAD tool vendors, researchers in industry, government and academia, professors and students, and systems engineers involved in microwave/mm-wave technology.

Multidisciplinary in scope, the journal publishes peer-reviewed articles and short papers on topics that include, but are not limited to. . .

- •Computer-Aided Modeling
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In addition, the scope of the journal includes features such as software reviews, microwave/mm-wave CAD related news, including brief reviews of CAD papers published elsewhere and a "Letters to the Editor" section.

Publication of *INTERNATIONAL JOURNAL OF MICROWAVE AND MILLIMETER-WAVE COMPUTER-AIDED ENGINEERING* is co-sponsored by the Center for Microwave and Millimeter-Wave CAD at the University of Colorado at Boulder. The Center, established by the National Science Foundation and supported by a consortium of industrial sponsors, is dedicated to research and development in microwave/millimeter-wave CAD.

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Manuscripts should be submitted to the Editor, Professor K. C. Gupta, MIMICAD Center, University of Colorado at Boulder, Campus Box 425, Boulder, CO 80309-0425. Telephone (303) 492-7498.

The contents of this journal are indexed or abstracted in: *Current Contents/ Engineering, Technology and Applied Sciences, SCISEARCH, the CompuMath Citation Index*, and *Research Alert*.

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